
None User Manual

General Description and Name

Attention!! Erasing a device with this scheme will permanently erase all the bad block marks. It will be impossible to recover this information once it has been lost, so this scheme should not be used for erasing or programming devices.

This method's main use is for reading the entire device including bad blocks to verify the proper operation of the scheme used to program the device.

Relevant User Options

The following special features on the special features tab apply to this scheme. The default values might work in some cases but please make sure to set the right value according to your system.

Please note only the below special feature items are related to this scheme and ignore any others. If any of below items doesn't exist, please check whether the right version has been installed or contact Data I/O for support by submitting Device Support Request through this address:

<http://www.dataio.com/support/dsr.asp>

Bad Block Handling Type = "None"

Spare area : Please refer to "Description of common NAND special features.pdf". *Normally set as "Disabled" for this BBM.*[Default 'Disabled']

Special Notes

If the device is erased with this method the entire spare area will be erased regardless of this selection.

This scheme should only be used for loading from a master device to verify the proper relocation of data that would have been mapped to a bad block. It will not report any bad blocks so it should not be used to program devices.

Revision History

V1.0 June 11, 2009
Create this spec.

Appendix

You can get the file “Description of common NAND special features.pdf” from
<http://ftp.dataio.com/FCNotes/BBM/>

Data I/O